



**U.S. Department of Commerce
Bureau of Industry and Security
Office of Technology Evaluation**



U.S. Microelectronics Industrial Base Assessment

The U.S. Department of Commerce's Bureau of Industry and Security (BIS), Office of Technology Evaluation (OTE) is conducting a comprehensive assessment of the U.S. microelectronics industrial base (MEIB). This assessment is being performed pursuant to Section 9904 of Title XCIX of the National Defense Authorization Act (NDAA) of Fiscal Year 2021. Title XCIX, Creating Helpful Incentives to Produce Semiconductors for America (CHIPS), contains multiple provisions related to promoting U.S. leadership in microelectronics and ensuring secure microelectronics supply chains. Section 9904 of the legislation, under which this data collection is mandated, requires the Secretary of Commerce to assess the capabilities of the U.S. microelectronics industrial base to support the national defense and includes a mandatory survey on the manufacture, design, and end use of microelectronics.

Your organization has been identified as a designer, manufacturer, and/or distributor of microelectronics in the United States. Your organization's participation is vital to ensure a comprehensive dataset for the assessment. OTE has worked in close partnership with industry in the past on a variety of assessments concerning U.S. industrial base sectors, and we anticipate similar cooperation from you on this effort.

The principal goal of this assessment is to better understand the domestic microelectronics network to support the national defense. The data collected will help identify the structure and interdependencies of organizations that participate in the MEIB. This effort will enable the U.S. government (USG) to understand and respond to supply chain deficiencies and disruptions related to diminishing manufacturing sources and material shortages (DMSMS), foreign sourcing and dependencies, critical minerals and materials, and other challenges. The resulting data and subsequent analysis will allow industry representatives and government policy officials to better monitor trends, benchmark industry performance, and raise awareness of potential issues of concern.

If your organization was contacted by OTE, your organization is required by federal law (50 U.S.C. § 4555) to complete the Microelectronics Industrial Base survey. All information submitted to OTE is protected as Business Confidential under provisions of the Defense Production Act (DPA) of 1950, as amended, and will not be published or publicly disclosed, other than in aggregate form. At no time will such reporting identify your specific organization. Such information is also protected from disclosure from Freedom of Information Act (FOIA) requests.

If your organization did not receive a distribution letter, but would like to participate in the assessment, contact OTE at SemiconductorStudy@bis.doc.gov or by phone at (202) 482-7808

To begin, download the Microsoft Excel-formatted survey and corresponding instructions by clicking on the hyperlink below. For internal data collection purposes, please refer to the PDF version of the survey containing callout boxes which display dropdown menu selections. The PDF version is only a reference document and cannot be submitted in place of the Excel survey.

Microelectronics Industrial Base Survey (Excel)*† | Microelectronics Industrial Base Survey (PDF)†

Complete and submit the Excel version at SemiconductorStudy@bis.doc.gov

*Save a copy of the Excel survey to your computer before inputting data.

†When clicking on the above links, if your computer does not ask if you want to download the file to your computer, right click on the link and select "Save As."

If you have any questions regarding the survey, OTE support staff are available to assist you by e-mail at SemiconductorStudy@bis.doc.gov or by phone at (202) 482-7808. E-mail is preferred and will permit a more thorough understanding of, and response to, any queries.

Thank you for your cooperation. We look forward to working with you.

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